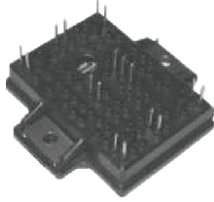


## 3-Levels Half Bridge Inverter Stage, 60 A, 57 A


**EMIPAK2**
**FEATURES**

- Warp1 and Warp2 PFC IGBT
- FRED Pt® and HEXFRED® antiparallel diodes
- FRED Pt® clamping diodes
- Integrated thermistor
- Square RBSOA
- Low internal inductances
- Low switching loss
- UL approved file E78996
- Material categorization: for definitions of compliance please see [www.vishay.com/doc?99912](http://www.vishay.com/doc?99912)


**RoHS**  
COMPLIANT

PRODUCT SUMMARY	
<b>1° LEVEL OF HALF-BRIDGE</b>	
$V_{CES}$	600 V
$V_{CE(ON)}$ typical at $I_C = 50$ A	1.8 V
$I_C$ at $T_C = 98$ °C	50 A
<b>2° LEVEL OF HALF-BRIDGE</b>	
$V_{CES}$	900 V
$V_{CE(ON)}$ typical at $I_C = 50$ A	2.73 V
$I_C$ at $T_C = 93$ °C	50 A
Speed	30 kHz to 150 kHz
Package	EMIPAK2
Circuit	3-levels half bridge inverter stage

**DESCRIPTION**

VS-EMF050J60U is an integrated solution for a multi level inverter half-bridge in a single package. The EMIPAK2 package is easy to use thanks to the solderable terminals and provides improved thermal performance thanks to the exposed substrate. The optimized layout also helps to minimize stray parameters, allowing for better EMI performance.

ABSOLUTE MAXIMUM RATINGS				
PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS
Operating junction temperature	$T_J$		150	°C
Storage temperature range	$T_{Stg}$		-40 to +125	
RMS isolation voltage	$V_{ISOL}$	$T_J = 25$ °C, all terminals shorted, $f = 50$ Hz, $t = 1$ s	3500	V
<b>Q1 - Q4 IGBT</b>				
Collector to emitter voltage	$V_{CES}$		600	V
Gate to emitter voltage	$V_{GES}$		20	
Pulsed collector current	$I_{CM}$		150	A
Clamped inductive load current	$I_{LM}^{(1)}$		150	
Continuous collector current	$I_C$	$T_C = 25$ °C	88	A
		$T_C = 80$ °C	60	
Power dissipation	$P_D$	$T_C = 25$ °C	338	W
		$T_C = 80$ °C	189	
<b>Q2 - Q3 IGBT</b>				
Collector to emitter voltage	$V_{CES}$		900	V
Gate to emitter voltage	$V_{GES}$		20	
Pulsed collector current	$I_{CM}$		150	A
Clamped inductive load current	$I_{LM}^{(2)}$		150	
Continuous collector current	$I_C$	$T_C = 25$ °C	85	A
		$T_C = 80$ °C	57	
Power dissipation	$P_D$	$T_C = 25$ °C	338	W
		$T_C = 80$ °C	189	



ABSOLUTE MAXIMUM RATINGS				
PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS
<b>D1 - D2 CLAMPING DIODE</b>				
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Single pulse forward current	$I_{FSM}$	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	270	A
Diode continuous forward current	$I_F$	$T_C = 25\text{ }^\circ\text{C}$	68	
		$T_C = 80\text{ }^\circ\text{C}$	46	
Power dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	150	W
		$T_C = 80\text{ }^\circ\text{C}$	84	
<b>D3 - D4 AP DIODE</b>				
Single pulse forward current	$I_{FSM}$	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	280	A
Diode continuous forward current	$I_F$	$T_C = 25\text{ }^\circ\text{C}$	53	
		$T_C = 80\text{ }^\circ\text{C}$	36	
Power dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	176	W
		$T_C = 80\text{ }^\circ\text{C}$	99	
<b>D5 - D6 AP DIODE</b>				
Single pulse forward current	$I_{FSM}$	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	220	A
Diode continuous forward current	$I_F$	$T_C = 25\text{ }^\circ\text{C}$	46	A
		$T_C = 80\text{ }^\circ\text{C}$	31	
Power dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	96	W
		$T_C = 80\text{ }^\circ\text{C}$	54	

**Notes**

- Absolute Maximum Ratings indicate sustained limits beyond which damage to the device may occur.
- (1)  $V_{CC} = 400\text{ V}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\text{ }\mu\text{H}$ ,  $R_g = 22\text{ }\Omega$ ,  $T_J = 150\text{ }^\circ\text{C}$
- (2)  $V_{CC} = 720\text{ V}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\text{ }\mu\text{H}$ ,  $R_g = 22\text{ }\Omega$ ,  $T_J = 150\text{ }^\circ\text{C}$

ELECTRICAL SPECIFICATIONS ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q1 - Q4 IGBT</b>						
Collector to emitter breakdown voltage	$BV_{CES}$	$V_{GE} = 0\text{ V}$ , $I_C = 500\text{ }\mu\text{A}$	600	-	-	V
Temperature coefficient of breakdown voltage	$\Delta BV_{CES}/\Delta T_J$	$V_{GE} = 0\text{ V}$ , $I_C = 500\text{ }\mu\text{A}$ ( $25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$ )	-	0.1	-	V/ $^\circ\text{C}$
Collector to emitter voltage	$V_{CE(ON)}$	$V_{GE} = 15\text{ V}$ , $I_C = 27\text{ A}$	-	1.44	1.75	V
		$V_{GE} = 15\text{ V}$ , $I_C = 50\text{ A}$	-	1.8	2.1	
		$V_{GE} = 15\text{ V}$ , $I_C = 27\text{ A}$ , $T_J = 125\text{ }^\circ\text{C}$	-	1.7	2.05	
		$V_{GE} = 15\text{ V}$ , $I_C = 50\text{ A}$ , $T_J = 125\text{ }^\circ\text{C}$	-	2.2	2.5	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}$ , $I_C = 250\text{ }\mu\text{A}$	2.9	3.9	5.3	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}$ , $I_C = 1\text{ mA}$ ( $25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$ )	-	-10	-	mV/ $^\circ\text{C}$
Forward transconductance	$g_{fe}$	$V_{CE} = 20\text{ V}$ , $I_C = 50\text{ A}$	-	95	-	s
Transfer characteristics	$V_{GE}$	$V_{CE} = 20\text{ V}$ , $I_C = 50\text{ A}$	-	5.9	-	V
Zero gate voltage collector current	$I_{CES}$	$V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$	-	0.003	0.1	mA
		$V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$ , $T_J = 125\text{ }^\circ\text{C}$	-	0.170	3	
Gate to emitter leakage current	$I_{GES}$	$V_{GE} = \pm 20\text{ V}$ , $V_{CE} = 0\text{ V}$	-	-	$\pm 200$	nA



<b>ELECTRICAL SPECIFICATIONS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q2 - Q3 IGBT</b>						
Collector to emitter breakdown voltage	$BV_{CES}$	$V_{GE} = 0\text{ V}, I_C = 500\text{ }\mu\text{A}$	900	-	-	V
Temperature coefficient of breakdown voltage	$\Delta BV_{CES}/\Delta T_J$	$V_{GE} = 0\text{ V}, I_C = 500\text{ }\mu\text{A}$ (25 °C to 125 °C)	-	-8.5	-	V/°C
Collector to emitter voltage	$V_{CE(ON)}$	$V_{GE} = 15\text{ V}, I_C = 27\text{ A}$	-	2.45	2.8	V
		$V_{GE} = 15\text{ V}, I_C = 50\text{ A}$	-	2.73	3.2	
		$V_{GE} = 15\text{ V}, I_C = 27\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	2	2.35	
		$V_{GE} = 15\text{ V}, I_C = 50\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	2.43	2.9	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}, I_C = 250\text{ }\mu\text{A}$	2.8	4.5	6.3	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}, I_C = 1\text{ mA}$ (25 °C to 125 °C)	-	-11.7	-	mV/°C
Forward transconductance	$g_{fe}$	$V_{CE} = 20\text{ V}, I_C = 50\text{ A}$	-	68	-	s
Transfer characteristics	$V_{GE}$	$V_{CE} = 20\text{ V}, I_C = 50\text{ A}$	-	6.9	-	V
Zero gate voltage collector current	$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 900\text{ V}$	-	0.006	0.38	mA
		$V_{GE} = 0\text{ V}, V_{CE} = 900\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	1.4	3	
Gate to emitter leakage current	$I_{GES}$	$V_{GE} = \pm 20\text{ V}, V_{CE} = 0\text{ V}$	-	-	$\pm 200$	nA
<b>D1 - D2 CLAMPING DIODE</b>						
Cathode to anode blocking voltage	$V_{BR}$	$I_R = 100\text{ }\mu\text{A}$	600	-	-	V
Forward voltage drop	$V_{FM}$	$I_F = 30\text{ A}$	-	1.84	2.12	
		$I_F = 30\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.37	1.65	
Reverse leakage current	$I_{RM}$	$V_R = 600\text{ V}$	-	0.002	0.1	mA
		$V_R = 600\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	0.9	6	
<b>D3 - D4 AP DIODE</b>						
Forward voltage drop	$V_{FM}$	$I_F = 50\text{ A}$	-	2.7	3.2	V
		$I_F = 50\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	2.8	3.3	
<b>D5 - D6 AP DIODE</b>						
Forward voltage drop	$V_{FM}$	$I_F = 30\text{ A}$	-	1.93	2.37	V
		$I_F = 30\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.48	1.9	



<b>SWITCHING CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q1 - Q4 IGBT (WITH FREEWHEELING D1 - D2 CLAMPING DIODE)</b>						
Total gate charge (turn-on)	$Q_g$	$I_C = 70\text{ A}$	-	480	720	nC
Gate to emitter charge (turn-on)	$Q_{ge}$	$V_{CC} = 400\text{ V}$	-	82	164	
Gate to collector charge (turn-on)	$Q_{gc}$	$V_{GE} = 15\text{ V}$	-	160	260	
Turn-on switching loss	$E_{ON}$	$I_C = 50\text{ A}$ $V_{CC} = 400\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}^{(1)}$	-	0.11	-	mJ
Turn-off switching loss	$E_{OFF}$		-	0.76	-	
Total switching loss	$E_{TOT}$		-	0.87	-	
Turn-on delay time	$t_{d(on)}$		-	182	-	ns
Rise time	$t_r$	-	46	-		
Turn-off delay time	$t_{d(off)}$	-	207	-		
Fall time	$t_f$	-	92	-		
Turn-on switching loss	$E_{ON}$	$I_C = 50\text{ A}$ $V_{CC} = 400\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	0.25	-	mJ
Turn-off switching loss	$E_{OFF}$		-	0.88	-	
Total switching loss	$E_{TOT}$		-	1.13	-	
Turn-on delay time	$t_{d(on)}$		-	183	-	ns
Rise time	$t_r$	-	47	-		
Turn-off delay time	$t_{d(off)}$	-	211	-		
Fall time	$t_f$	-	101	-		
Input capacitance	$C_{ies}$	$V_{GE} = 0\text{ V}$	-	9500		pF
Output capacitance	$C_{oes}$	$V_{CC} = 30\text{ V}$	-	780		
Reverse transfer capacitance	$C_{res}$	$f = 1\text{ MHz}$	-	116		
Reverse bias safe operating area	RBSOA	$T_J = 150\text{ }^\circ\text{C}$ , $I_C = 150\text{ A}$ $V_{CC} = 400\text{ V}$ , $V_P = 600\text{ V}$ $R_g = 22\text{ }\Omega$ , $V_{GE} = 15\text{ V to } 0\text{ V}$	Fullsquare			
<b>Q2 - Q3 IGBT (WITH FREEWHEELING D3 - D4 AP DIODE)</b>						
Total gate charge (turn-on)	$Q_g$	$I_C = 50\text{ A}$	-	320	480	nC
Gate to emitter charge (turn-on)	$Q_{ge}$	$V_{CC} = 400\text{ V}$	-	38	58	
Gate to collector charge (turn-on)	$Q_{gc}$	$V_{GE} = 15\text{ V}$	-	106	160	
Turn-on switching loss	$E_{ON}$	$I_C = 50\text{ A}$ $V_{CC} = 720\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}^{(1)}$	-	0.56	-	mJ
Turn-off switching loss	$E_{OFF}$		-	0.68	-	
Total switching loss	$E_{TOT}$		-	1.24	-	
Turn-on delay time	$t_{d(on)}$		-	152	-	ns
Rise time	$t_r$	-	48	-		
Turn-off delay time	$t_{d(off)}$	-	165	-		
Fall time	$t_f$	-	100	-		
Turn-on switching loss	$E_{ON}$	$I_C = 50\text{ A}$ $V_{CC} = 720\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	0.95	-	mJ
Turn-off switching loss	$E_{OFF}$		-	2.18	-	
Total switching loss	$E_{TOT}$		-	3.13	-	
Turn-on delay time	$t_{d(on)}$		-	154	-	ns
Rise time	$t_r$	-	52	-		
Turn-off delay time	$t_{d(off)}$	-	168	-		
Fall time	$t_f$	-	360	-		
Input capacitance	$C_{ies}$	$V_{GE} = 0\text{ V}$	-	6600	-	pF
Output capacitance	$C_{oes}$	$V_{CC} = 30\text{ V}$	-	400	-	
Reverse transfer capacitance	$C_{res}$	$f = 1\text{ MHz}$	-	90	-	
Reverse bias safe operating area	RBSOA	$T_J = 150\text{ }^\circ\text{C}$ , $I_C = 150\text{ A}$ $V_{CC} = 720\text{ V}$ , $V_P = 900\text{ V}$ $R_g = 22\text{ }\Omega$ , $V_{GE} = 15\text{ V to } 0\text{ V}$	Fullsquare			



<b>SWITCHING CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>D1 - D2 CLAMPING DIODE</b>						
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$ $I_F = 30\text{ A}$ $di/dt = 500\text{ A}/\mu\text{s}$	-	50	80	ns
Diode peak reverse current	$I_{rr}$		-	7.5	11	A
Diode recovery charge	$Q_{rr}$		-	185	440	nC
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$ $I_F = 30\text{ A}$ $di/dt = 500\text{ A}/\mu\text{s}, T_J = 125\text{ }^\circ\text{C}$	-	107	147	ns
Diode peak reverse current	$I_{rr}$		-	18	22	A
Diode recovery charge	$Q_{rr}$		-	955	1620	nC
<b>D3 - D4 AP DIODE</b>						
Diode reverse recovery time	$t_{rr}$	$V_R = 400\text{ V}$ $I_F = 50\text{ A}$ $di/dt = 500\text{ A}/\mu\text{s}$	-	114	150	ns
Diode peak reverse current	$I_{rr}$		-	21	25	A
Diode recovery charge	$Q_{rr}$		-	1200	1875	nC
Diode reverse recovery time	$t_{rr}$	$V_R = 400\text{ V}$ $I_F = 50\text{ A}$ $di/dt = 500\text{ A}/\mu\text{s}, T_J = 125\text{ }^\circ\text{C}$	-	170	210	ns
Diode peak reverse current	$I_{rr}$		-	28	32	A
Diode recovery charge	$Q_{rr}$		-	2160	3360	nC
<b>D5 - D6 AP DIODE</b>						
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$ $I_F = 30\text{ A}$ $di/dt = 500\text{ A}/\mu\text{s}$	-	46	77	ns
Diode peak reverse current	$I_{rr}$		-	7	11	A
Diode recovery charge	$Q_{rr}$		-	161	423	nC
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$ $I_F = 30\text{ A}$ $di/dt = 500\text{ A}/\mu\text{s}, T_J = 125\text{ }^\circ\text{C}$	-	106	138	ns
Diode peak reverse current	$I_{rr}$		-	17	22	A
Diode recovery charge	$Q_{rr}$		-	900	1518	nC

**Note**

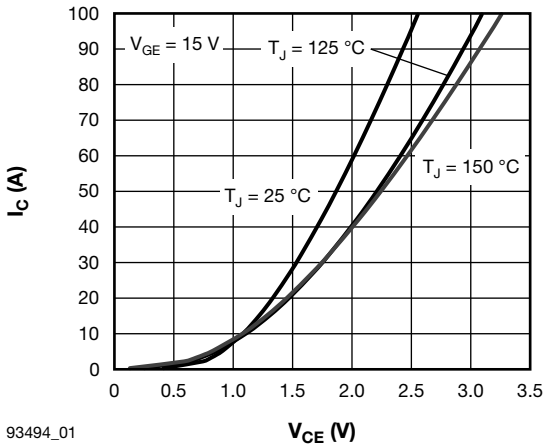
(1) Energy losses include "tail" and diode reverse recovery.

<b>THERMISTOR ELECTRICAL CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Resistance	$R_{25}$		4500	5000	5500	$\Omega$
	$R_{100}$	$T_J = 100\text{ }^\circ\text{C}$	468	493	518	
B value	B	$T_J = 25\text{ }^\circ\text{C}/T_J = 50\text{ }^\circ\text{C}$	3206	3375	3544	K

<b>THERMAL AND MECHANICAL SPECIFICATIONS</b>						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNITS	
Q1 - Q4 IGBT - Junction to case thermal resistance (per switch)	$R_{thJC}$	-	-	0.37	$^\circ\text{C}/\text{W}$	
Q2 - Q3 IGBT - Junction to case thermal resistance (per switch)		-	-	0.37		
D1 - D2 Clamping diode - Junction to case thermal resistance (per diode)		-	-	0.83		
D3 - D4 AP diode - Junction to case thermal resistance (per diode)		-	-	0.71		
D5 - D6 AP diode - Junction to case thermal resistance (per diode)		-	-	1.3		
Q1 - Q4 IGBT - Case to sink thermal resistance (per switch)	$R_{thCS}^{(1)}$	-	0.31	-		
Q2 - Q3 IGBT - Case to sink thermal resistance (per switch)		-	0.31	-		
D1 - D2 Clamping diode - Case to sink thermal resistance (per diode)		-	0.51	-		
D3 - D4 AP diode - Case to sink thermal resistance (per diode)		-	0.41	-		
D5 - D6 AP diode - Case to sink thermal resistance (per diode)		-	0.62	-		
Mounting torque (M4)		2	-	3	Nm	
Weight		-	39	-	g	

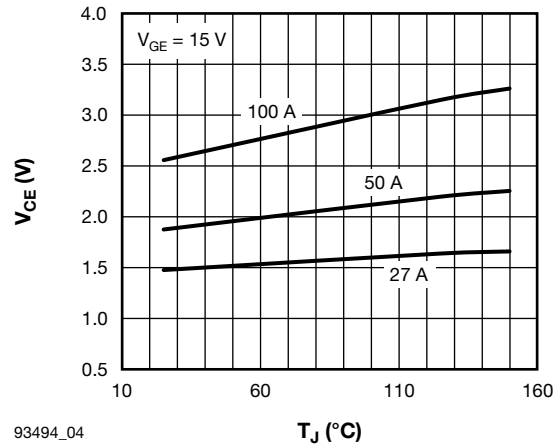
**Note**

(1) Mounting surface flat, smooth, and greased



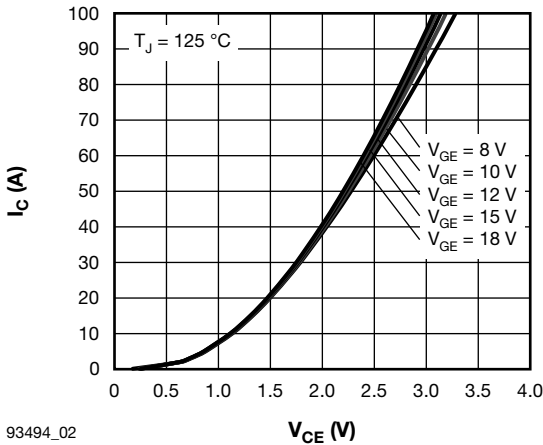
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Fig. 1 - Typical Q1 - Q4 IGBT Output Characteristics



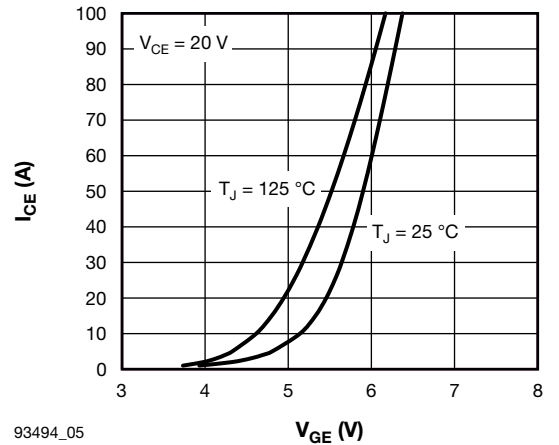
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Fig. 4 - Typical Q1 - Q4 IGBT Collector to Emitter Voltage vs. Junction Temperature



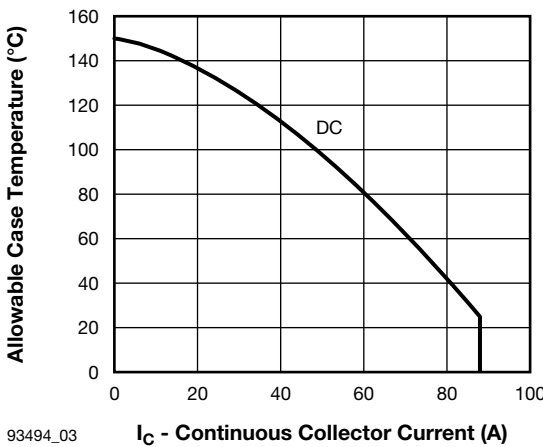
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Fig. 2 - Typical Q1 - Q4 IGBT Output Characteristics



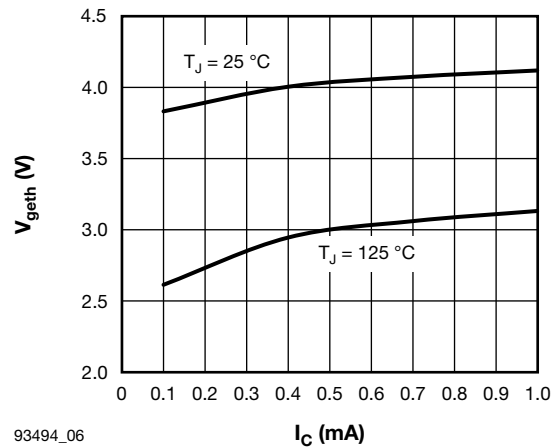
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Fig. 5 - Typical Q1 - Q4 IGBT Transfer Characteristics



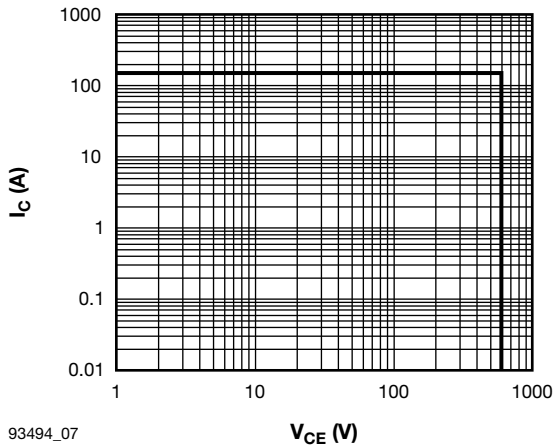
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Fig. 3 - Maximum DC Q1 - Q4 IGBT Collector Current vs. Case Temperature per Junction



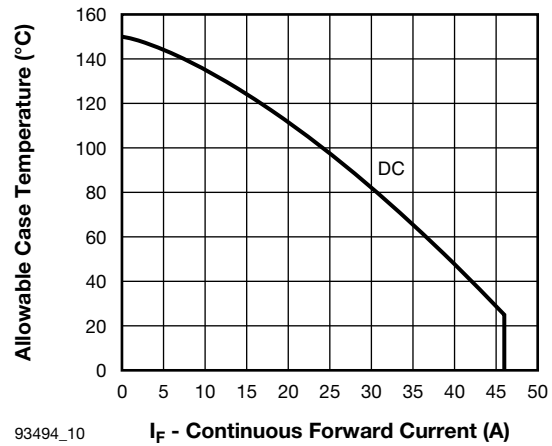
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Fig. 6 - Typical Q1 - Q4 IGBT Gate Threshold Voltage



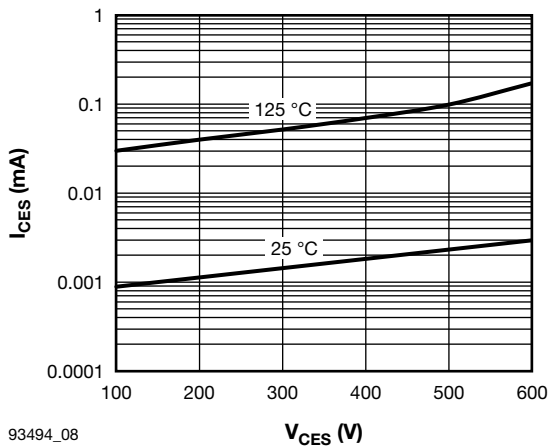
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Fig. 7 - Q1 - Q4 IGBT Reverse Bias SOA  
 $T_J = 150\text{ }^\circ\text{C}$ ,  $V_{GE} = 15\text{ V}$ ,  $R_g = 22\ \Omega$



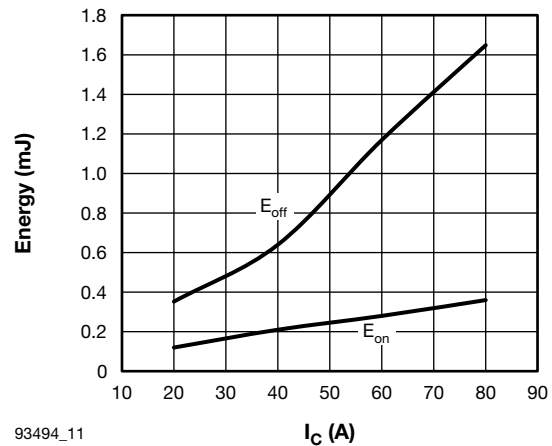
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Fig. 10 - Maximum DC D5 - D6 Antiparallel Diode Forward Current vs. Case Temperature per Junction



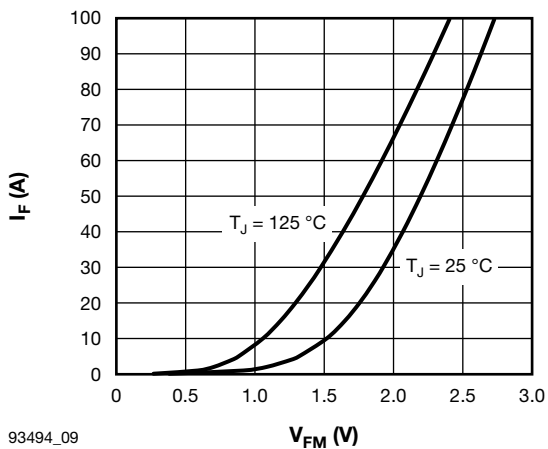
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Fig. 8 - Typical Q1 - Q4 IGBT Zero Gate Voltage Collector Current



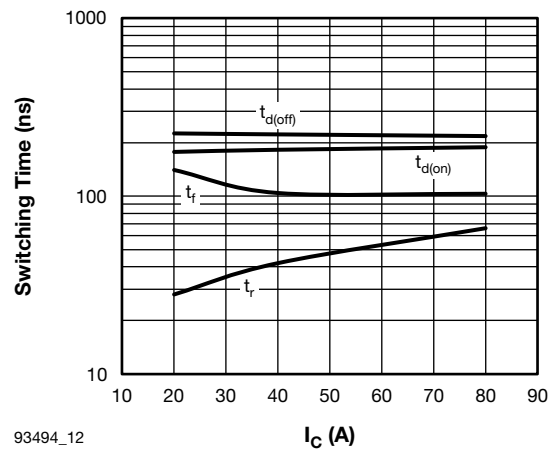
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Fig. 11 - Typical Q1 - Q4 IGBT Energy Loss vs.  $I_C$  (with Freewheeling D1 - D2 Clamping Diode)  
 $V_{CC} = 400\text{ V}$ ,  $R_g = 4.7\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$



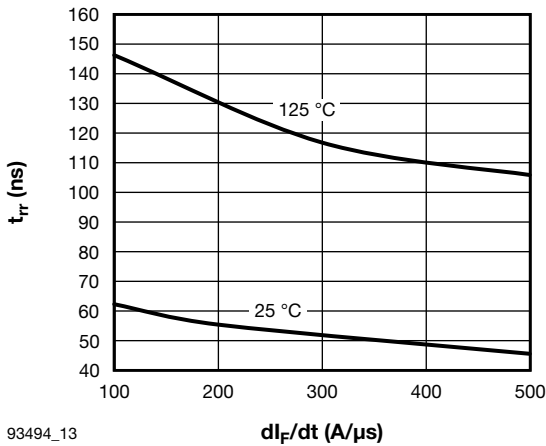
93494\_09

Fig. 9 - Typical D5 - D6 Antiparallel Diode Forward Characteristics



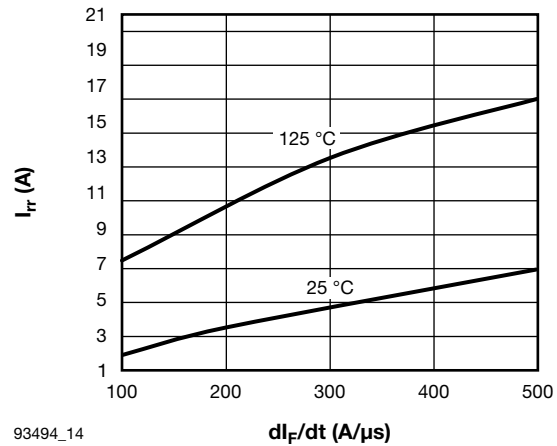
93494\_12

Fig. 12 - Typical Q1 - Q4 IGBT Switching Time vs.  $I_C$  (with Freewheeling D1 - D2 Clamping Diode)  
 $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 400\text{ V}$ ,  $R_g = 4.7\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$



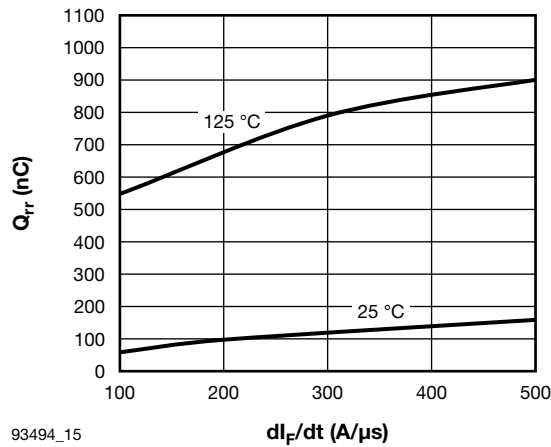
93494\_13

Fig. 13 - Typical D5 - D6 Antiparallel Diode Reverse Recovery Time vs.  $di_F/dt$   
 $V_R = 200\text{ V}$ ,  $I_F = 30\text{ A}$



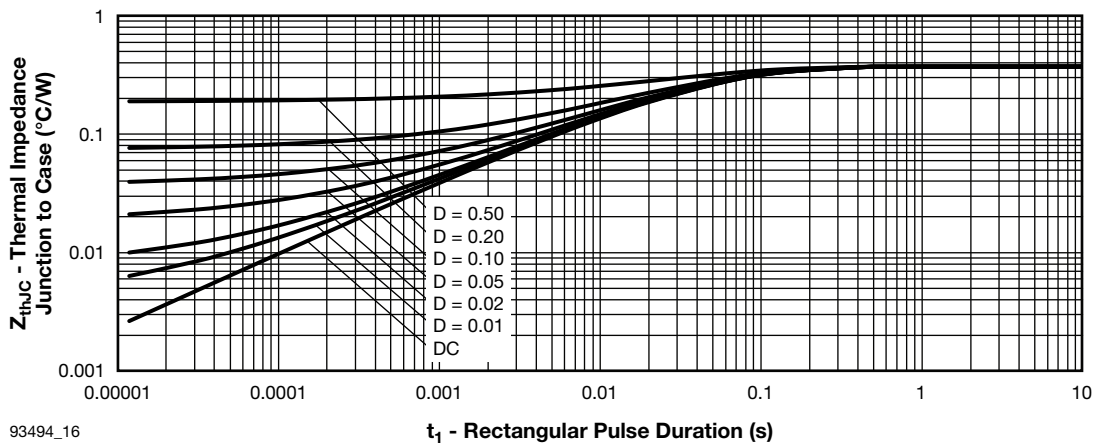
93494\_14

Fig. 14 - Typical D5 - D6 Antiparallel Diode Reverse Recovery Current vs.  $di_F/dt$   
 $V_R = 200\text{ V}$ ,  $I_F = 30\text{ A}$



93494\_15

Fig. 15 - Typical D5 - D6 Antiparallel Diode Reverse Recovery Charge vs.  $di_F/dt$   
 $V_R = 200\text{ V}$ ,  $I_F = 30\text{ A}$



93494\_16

Fig. 16 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (Q1 - Q4 IGBT)



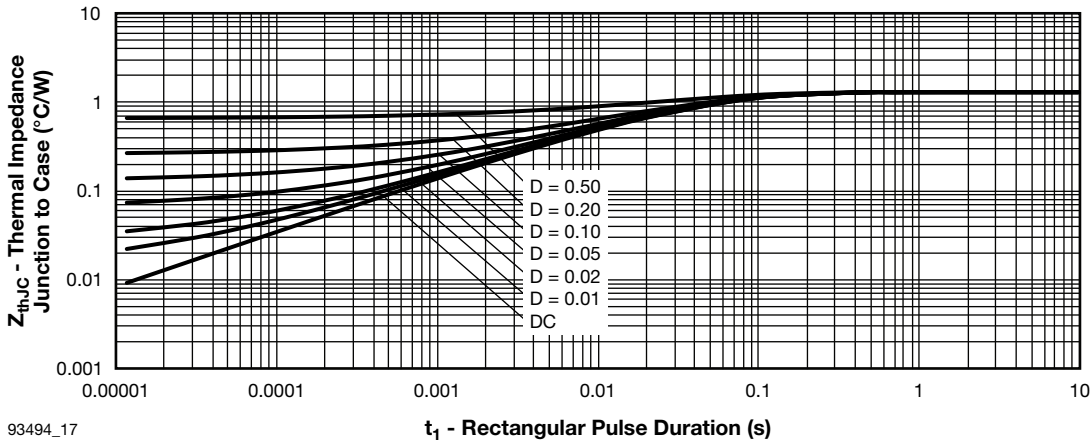


Fig. 17 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (D5 - D6 Antiparallel Diode)

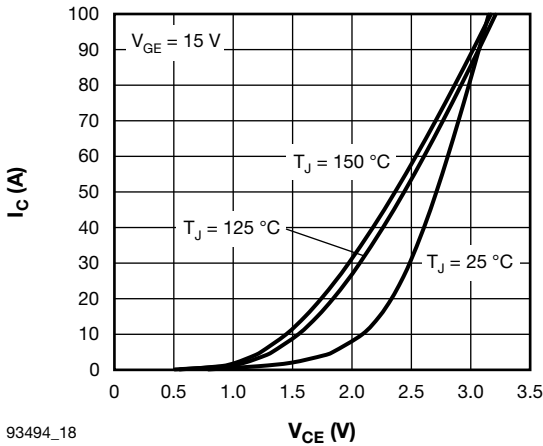


Fig. 18 - Typical Q2 - Q3 IGBT Output Characteristics

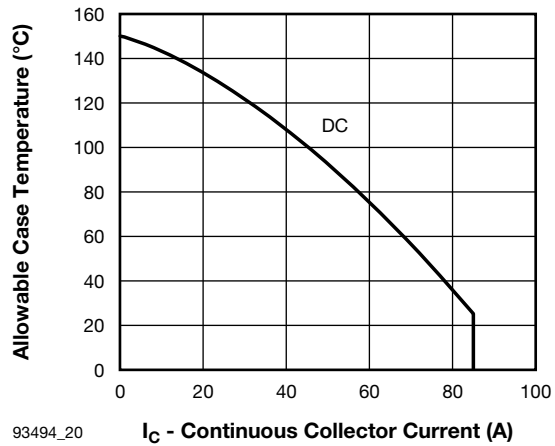


Fig. 20 - Maximum DC Q2 - Q3 IGBT Collector Current vs. Case Temperature per Junction

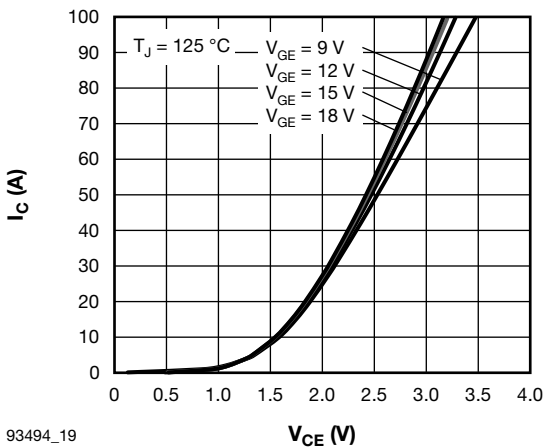


Fig. 19 - Typical Q2 - Q3 IGBT Output Characteristics

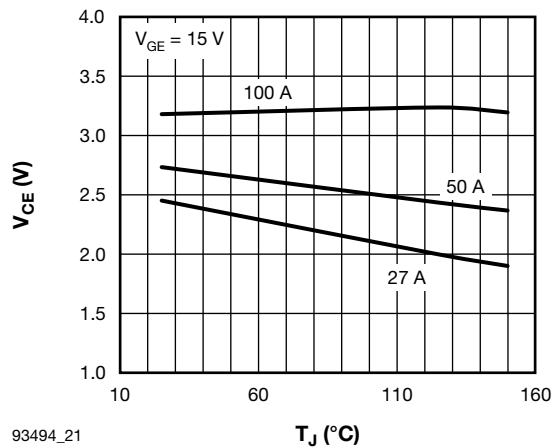
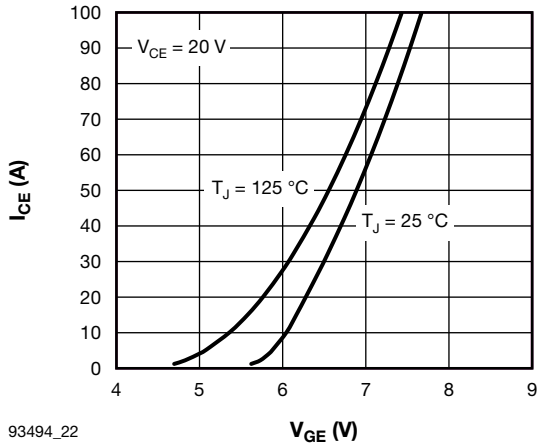
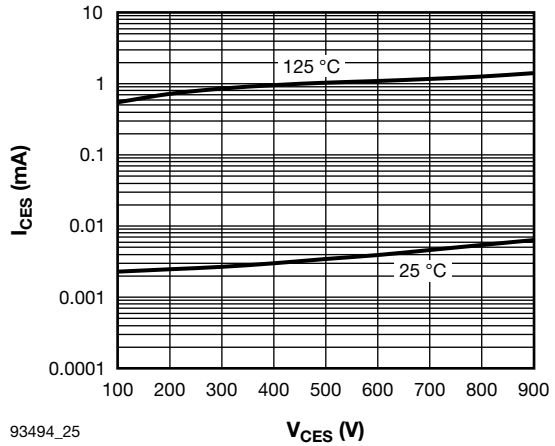


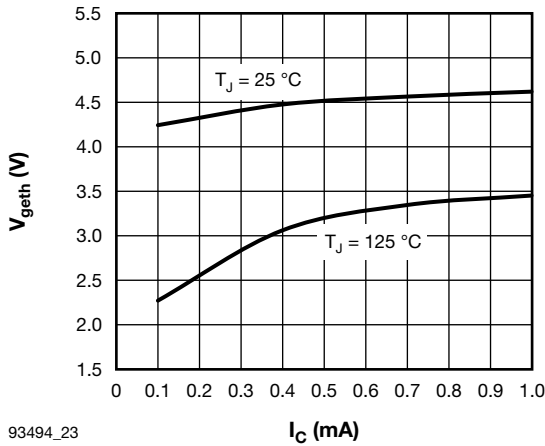
Fig. 21 - Typical Q2 - Q3 IGBT Collector to Emitter Voltage vs. Junction Temperature



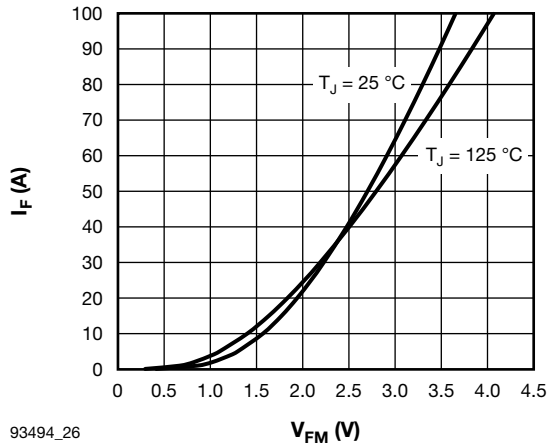
93494\_22  
Fig. 22 - Typical Q1 - Q4 IGBT Transfer Characteristics



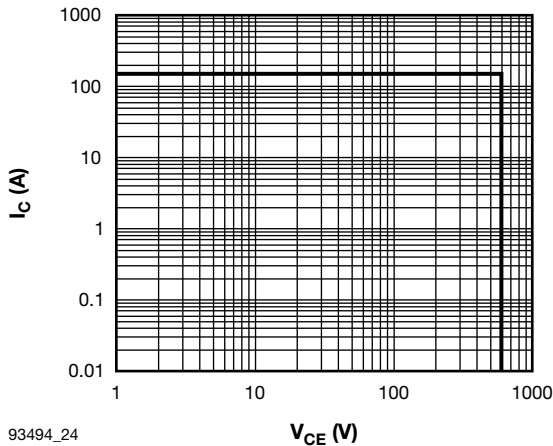
93494\_25  
Fig. 25 - Typical Q2 - Q3 IGBT Zero Gate Voltage Collector Current



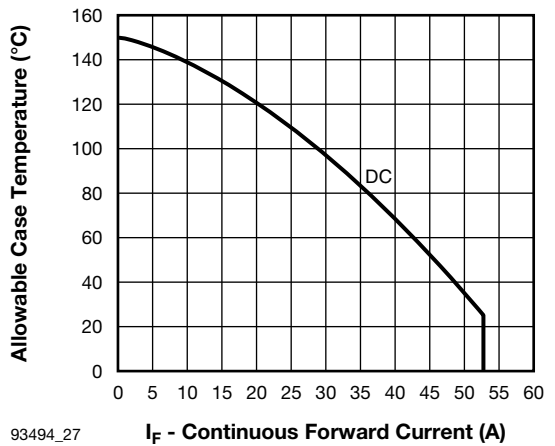
93494\_23  
Fig. 23 - Typical Q2 - Q3 IGBT Gate Threshold Voltage



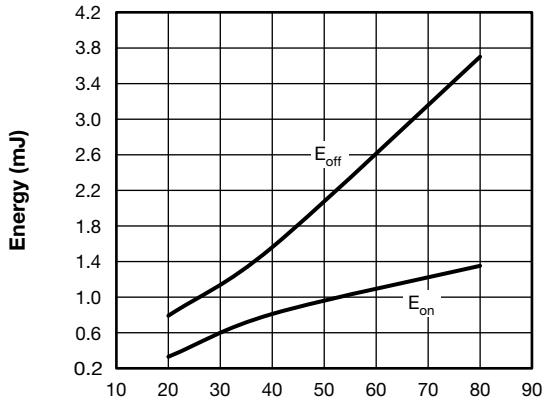
93494\_26  
Fig. 26 - Typical D3 - D4 Antiparallel Diode Forward Characteristics



93494\_24  
Fig. 24 - Q2 - Q3 IGBT Reverse Bias SOA  
 $T_J = 150\text{ °C}$ ,  $V_{GE} = 15\text{ V}$ ,  $R_g = 22\ \Omega$



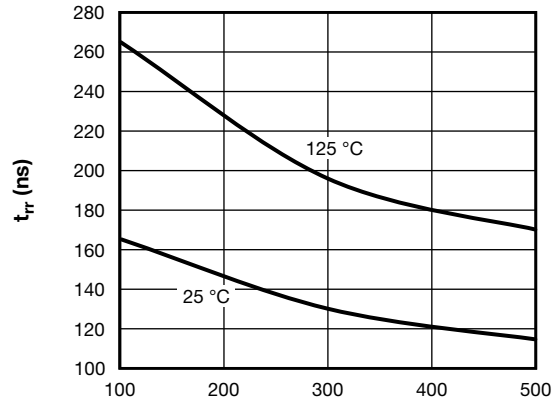
93494\_27  
Fig. 27 - Maximum DC D3 - D4 Antiparallel Diode Forward Current vs. Case Temperature per Junction



93494\_28

**I<sub>C</sub> (A)**

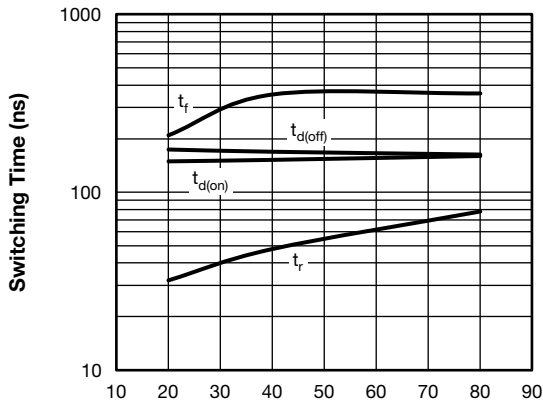
Fig. 28 - Typical Q2 - Q3 IGBT Energy Loss vs. I<sub>C</sub> (with Freewheeling D2 - D3 AP Diode)  
V<sub>CC</sub> = 720 V, R<sub>g</sub> = 4.7 Ω, V<sub>GE</sub> = 15 V, L = 500 μH



93494\_30

**di<sub>F</sub>/dt (A/μs)**

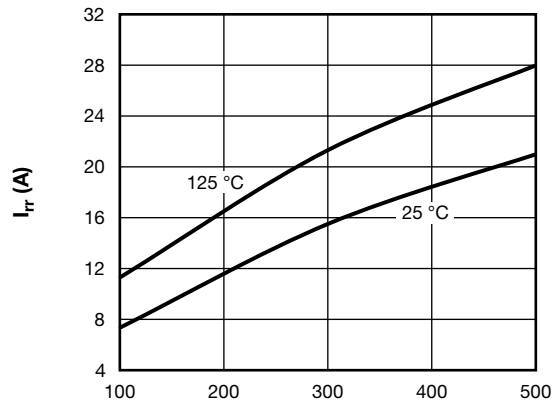
Fig. 30 - Typical D3 - D4 Antiparallel Diode Reverse Recovery Time vs. di<sub>F</sub>/dt  
V<sub>R</sub> = 400 V, I<sub>F</sub> = 50 A



93494\_29

**I<sub>C</sub> (A)**

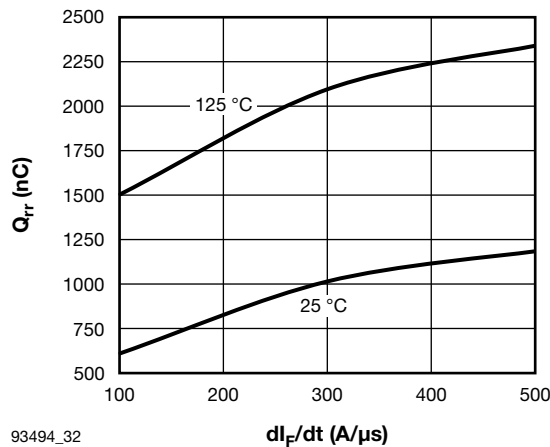
Fig. 29 - Typical Q2 - Q3 IGBT Switching Time vs. I<sub>C</sub> (with Freewheeling D2 - D3 AP Diode)  
T<sub>J</sub> = 125 °C, V<sub>CC</sub> = 720 V, R<sub>g</sub> = 4.7 Ω, V<sub>GE</sub> = 15 V, L = 500 μH



93494\_31

**di<sub>F</sub>/dt (A/μs)**

Fig. 31 - Typical D3 - D4 Antiparallel Diode Reverse Recovery Current vs. di<sub>F</sub>/dt  
V<sub>R</sub> = 400 V, I<sub>F</sub> = 50 A



93494\_32

**di<sub>F</sub>/dt (A/μs)**

Fig. 32 - Typical D3 - D4 Antiparallel Diode Reverse Recovery Charge vs. di<sub>F</sub>/dt  
V<sub>R</sub> = 400 V, I<sub>F</sub> = 50 A

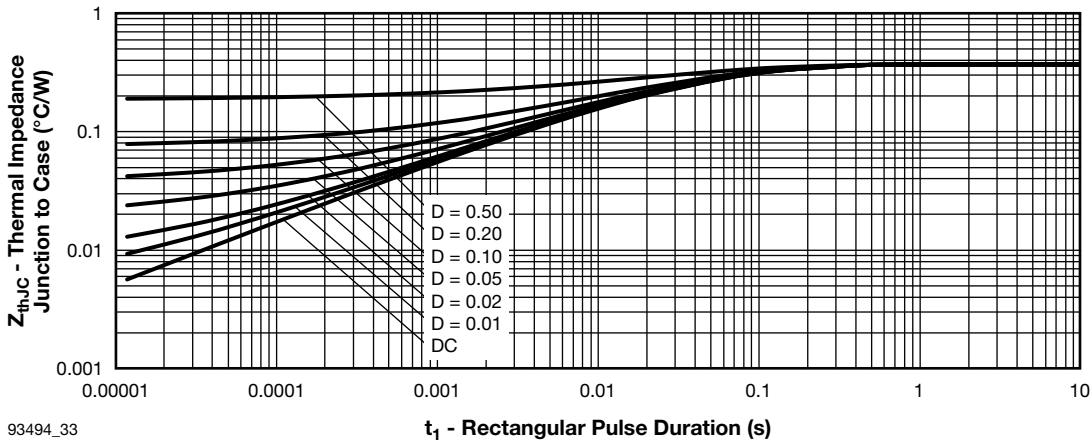


Fig. 33 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (Q2 - Q3 IGBT)

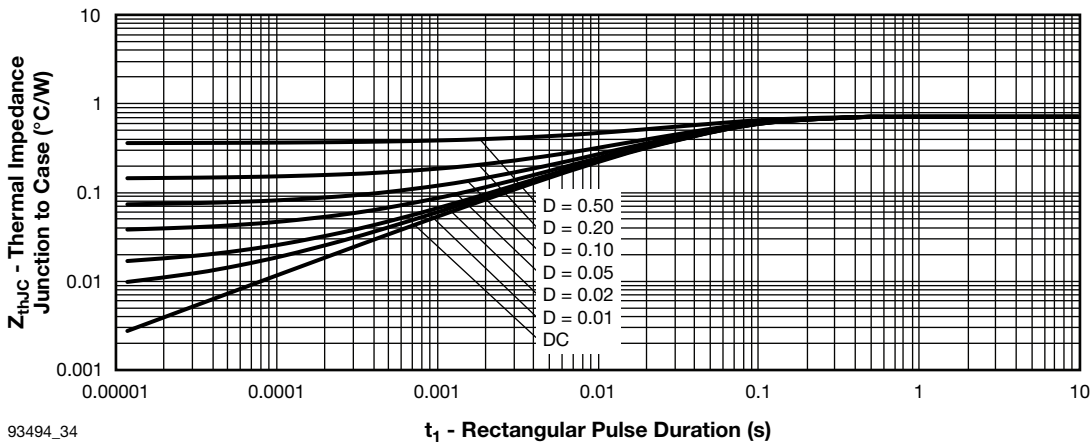


Fig. 34 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (D3 - D4 Antiparallel Diode)

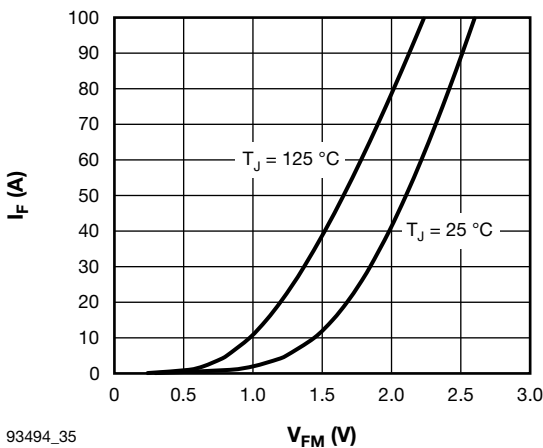


Fig. 35 - Typical D1 - D2 Clamping Diode Forward Characteristics

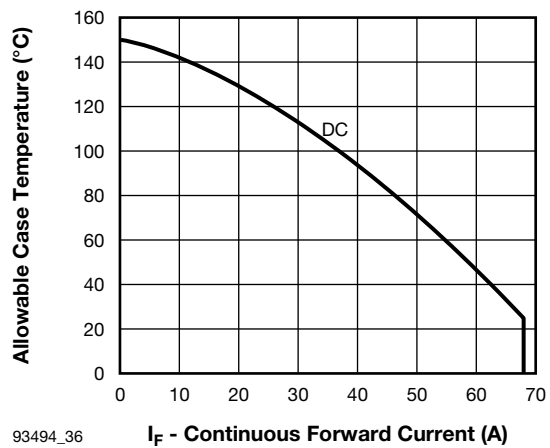
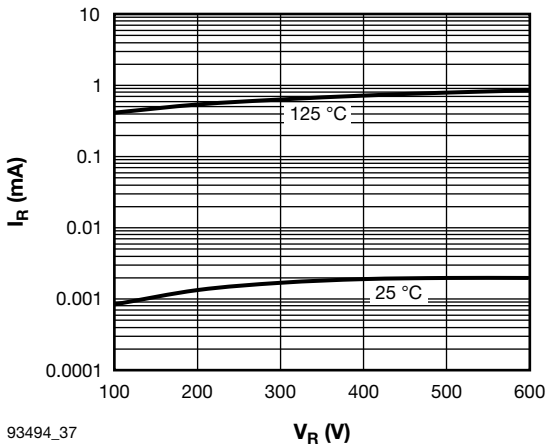
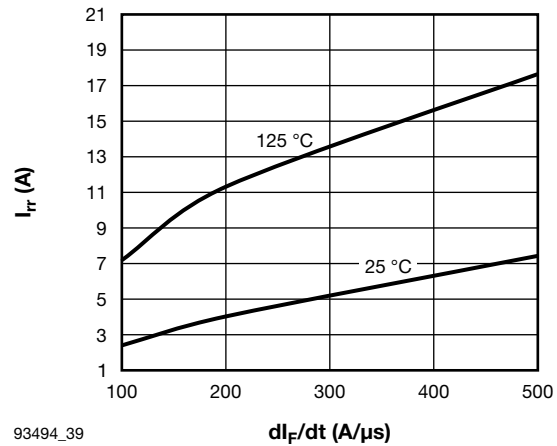


Fig. 36 - Maximum DC D1 - D2 Clamping Diode Forward Current vs. Case Temperature per Junction



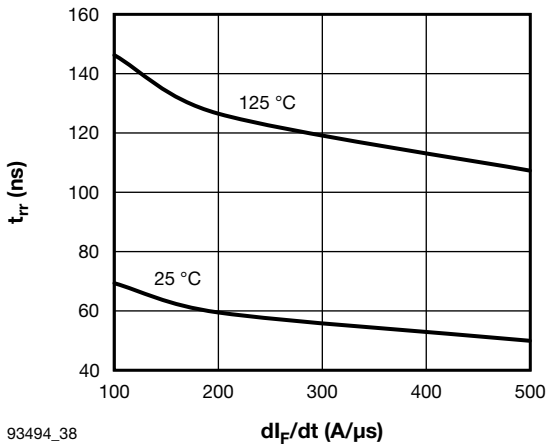
93494\_37

Fig. 37 - Typical D1 - D2 Clamping Diode Reverse Leakage Current



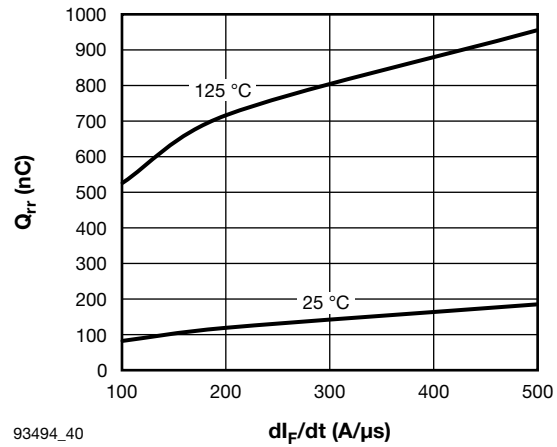
93494\_39

Fig. 39 - Typical D1 - D2 Clamping Diode Reverse Recovery Current vs.  $di_F/dt$   
 $V_R = 200\text{ V}$ ,  $I_F = 30\text{ A}$



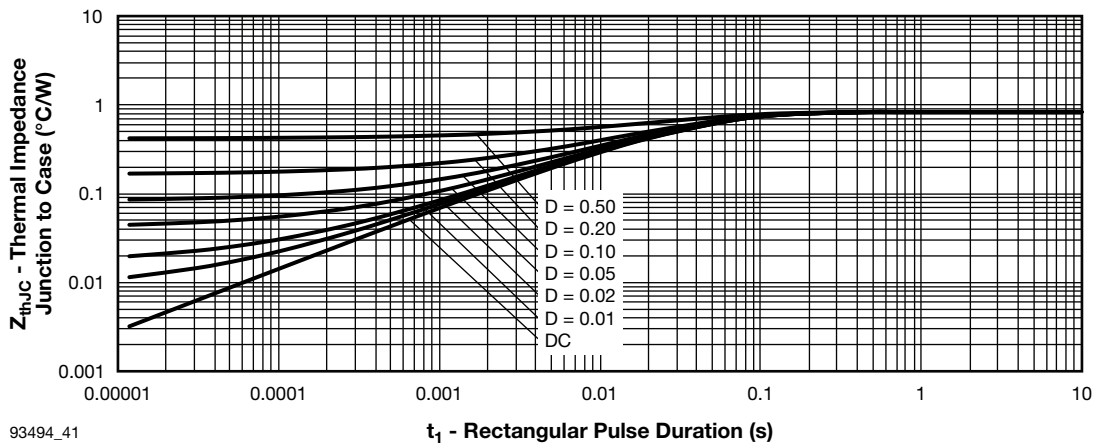
93494\_38

Fig. 38 - Typical D1 - D2 Clamping Diode Reverse Recovery Time vs.  $di_F/dt$   
 $V_R = 200\text{ V}$ ,  $I_F = 30\text{ A}$



93494\_40

Fig. 40 - Typical D1 - D2 Clamping Diode Reverse Recovery Charge vs.  $di_F/dt$   
 $V_R = 200\text{ V}$ ,  $I_F = 30\text{ A}$



93494\_41

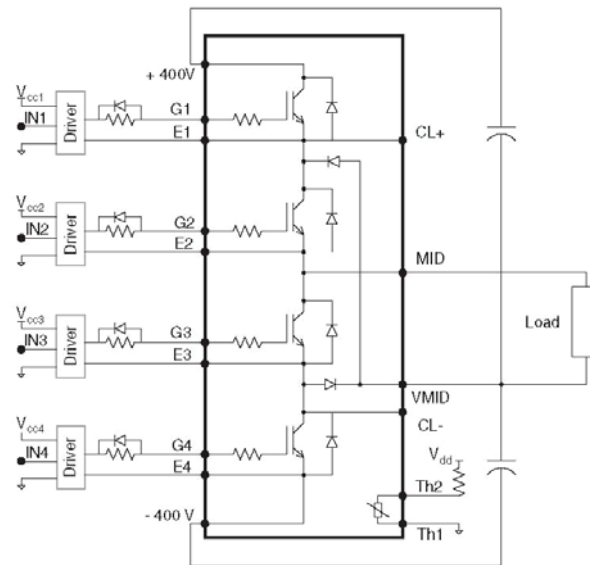
Fig. 41 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (D1 - D2 Clamping Diode)

## ORDERING INFORMATION TABLE

Device code	<b>VS-</b>	<b>EM</b>	<b>F</b>	<b>050</b>	<b>J</b>	<b>60</b>	<b>U</b>
	①	②	③	④	⑤	⑥	⑦

- 1** - Vishay Semiconductors product
- 2** - Package indicator (EM = EMIPAK2)
- 3** - Circuit configuration (F = 3-levels half-bridge inverter stage)
- 4** - Current rating (050 = 50 A)
- 5** - Die technology (J = Warp2 IGBT)
- 6** - Voltage rating (60 = 600 V)
- 7** - U = Ultrafast

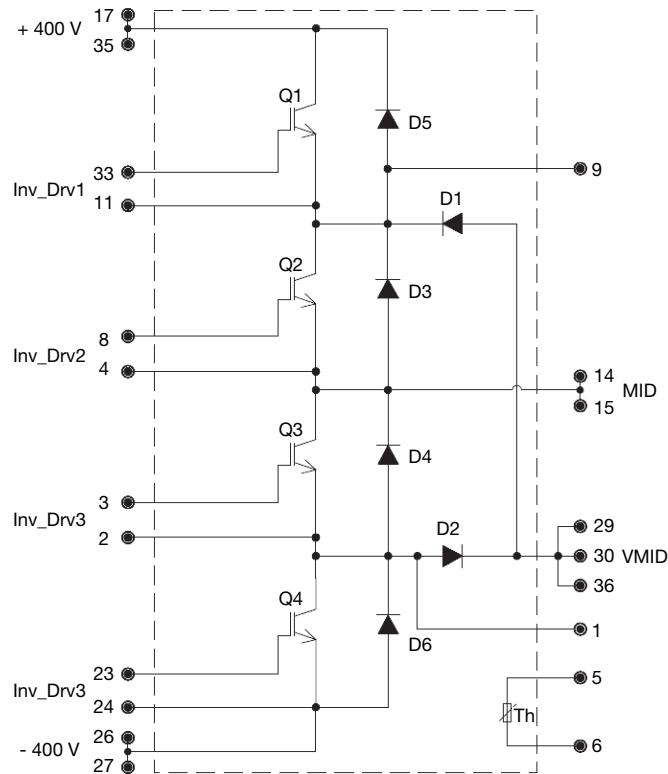
## TYPICAL CONNECTION



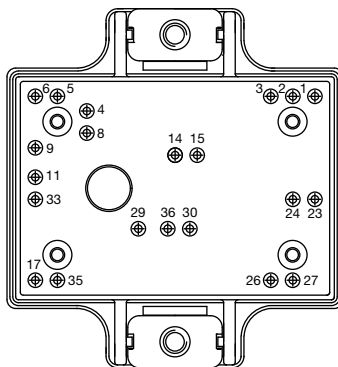
### Note

- Please refer to lead assignment for correct pin configuration. This diagram shows electrical connections only.

## CIRCUIT CONFIGURATION



## PACKAGE



### LINKS TO RELATED DOCUMENTS

Dimensions	<a href="http://www.vishay.com/doc?95436">www.vishay.com/doc?95436</a>
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